

F9310-VB Datasheet

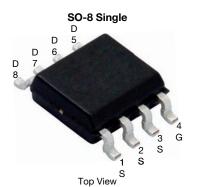
P-Channel 30 V (D-S) MOSFET

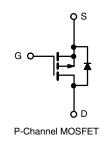
PRODUCT SUMMARY					
V _{DS} (V)	-30				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 \text{ V}$	0.0050				
$R_{DS(on)}$ (Ω) at $V_{GS} = 4.5 \text{ V}$	0.0080				
Q _g typ. (nC)	27				
I _D (A)	18				
Configuration	Single				

FEATURES

- Trench Gen IV p-channel power MOSFET
- Enables higher power density
- 100 % R_g and UIS tested







APPLICATIONS

- Battery management in mobile devices
- · Adapter and charger switch
- · Battery switch
- · Load switch

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V _{DS}	-30	V	
Gate-source voltage		V _{GS}	± 20	v	
	T _C = 25 °C		-18		
Continuous drain august (T. 150 °C)	T _C = 70 °C	1 , \sqsubset	-13		
Continuous drain current (T _J = 150 °C)	T _A = 25 °C	I _D	-11		
	T _A = 70 °C	1 -	-8	А	
Pulsed drain current (t = 100 μs)		I _{DM}	-145	A	
Continuous source-drain diode current	T _C = 25 °C		-5		
	T _A = 25 °C	ls —	-2.8 ^{b, c}		
Single pulse avalanche current	l 0.1 mll	I _{AS}	-25		
Single pulse avalanche energy	L = 0.1 mH	E _{AS}	31.2	mJ	
Maximum power dissipation	T _C = 25 °C		5.6		
	T _C = 70 °C	1 , \Box	3.6	w	
	T _A = 25 °C	I _P	3.1 b, c	VV	
	T _A = 70 °C]	2 b, c		
Operating junction and storage temperature range		T _J , T _{stg}	-55 to +150	°C	
Soldering recommendations (peak tempera		260			

THERMAL RESISTANCE RATINGS								
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT				
Maximum junction-to-ambient ^b	t ≤ 10 s	R_{thJA}	34	40	°C/W			
Maximum junction-to-case (drain)	Steady state	R_{thJF}	18	22	C/VV			

Notes

- Notes
 a. Package limited
 b. Surface mounted on 1" x 1" FR4 board
 c. t = 10 s
 d. The SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
- Rework conditions: manual soldering with a soldering iron is not recommended for leadless components Maximum under steady state conditions is 85 °C/W
- g. $T_C = 25$ °C



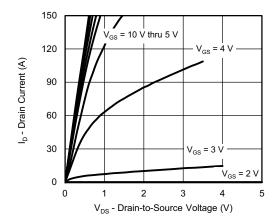
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-source breakdown voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-30	-	-	V	
V _{DS} temperature coefficient	$\Delta V_{DS}/T_{J}$	I _D = -10 mA	-	-17	-		
V _{GS(th)} temperature coefficient	$\Delta V_{GS(th)}/T_J$	5 0		5.5	-	mV/°C	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	-1	-	-2.2	V	
Gate-source leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = +16 \text{ / } -20 \text{ V}$	-	-	100	nA	
Zero gate voltage drain current		$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	— uA ∣	
	I _{DSS}	V _{DS} = -30 V, V _{GS} = 0 V, T _J = 70 °C	-	-	-15		
On-state drain current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	-40	-	-	Α	
Duning and the second of the s	Б	$V_{GS} = -10 \text{ V}, I_D = -15 \text{ A}$	-	0.0050	-	Ω	
Drain-source on-state resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -10 \text{ A}$	-	0.0080	-		
Forward transconductance a	9 _{fs}	$V_{DS} = -15 \text{ V}, I_D = -15 \text{ A}$	-	81	-	S	
Dynamic ^b						•	
Input capacitance	C _{iss}		-	3490	-	pF	
Output capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1420	-		
Reverse transfer capacitance	C _{rss}		-	70	-		
Total gate charge	Qg	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -10 \text{ A}$	-	56	84	nC	
			-	27	41		
Gate-source charge	Q _{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$	-	9.4	-		
Gate-drain charge	Q_{gd}		-	8.2	-		
Gate resistance	R_g	f = 1 MHz	1.5	3.5	6	Ω	
Turn-on delay time	t _{d(on)}		-	15	30		
Rise time	t _r	$V_{DD} = -15 \text{ V}, R_L = 1.5 \Omega, I_D \cong -10 \text{ A},$	-	6	12		
Turn-off delay time	t _{d(off)}	$V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$	-	39	78	1	
Fall time	t _f		-	10	20	1	
Turn-on delay time	t _{d(on)}		-	34	68	ns	
Rise time	t _r	V_{DD} = -15 V, R_L = 1.5 Ω , I_D \cong -10 A,	-	86	172	- - -	
Turn-off delay time	t _{d(off)}	V_{GEN} = -4.5 V, R_g = 1 Ω	-	31	62		
Fall time	t _f		-	22	44		
Drain-Source Body Diode Characteristi	cs						
Continuous source-drain diode current	Is	T _C = 25 °C	-	-	-5	_	
Pulse diode forward current	I _{SM}		-	-	-150	A	
Body diode voltage	V_{SD}	$I_{S} = -5 \text{ A}, V_{GS} = 0 \text{ V}$	-	-0.73	-1.1	V	
Body diode reverse recovery time	t _{rr}		-	44	88	ns	
Body diode reverse recovery charge	Q_{rr}	10 A 41/44 100 A/4- T 25 20	-	41	82	nC	
Reverse recovery fall time	t _a	$I_F = -10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	19	-		
Reverse recovery rise time	t _b		-	25	-	ns	

Notes

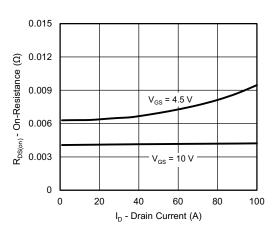
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

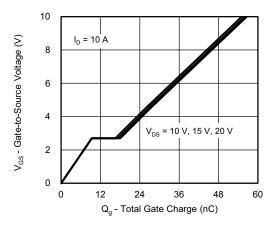




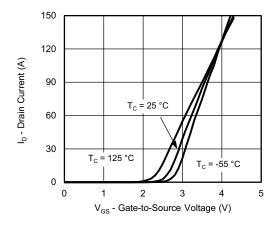
Output Characteristics



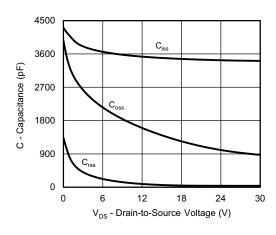
On-Resistance vs. Drain Current and Gate Voltage



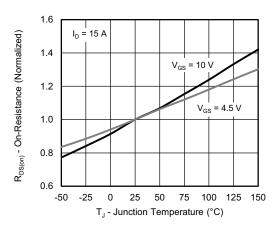
Gate Charge



Transfer Characteristics

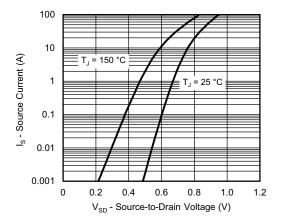


Capacitance

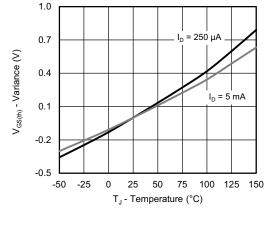


On-Resistance vs. Junction Temperature

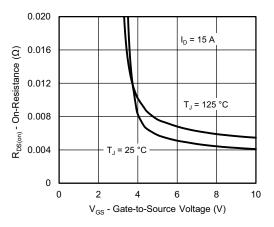




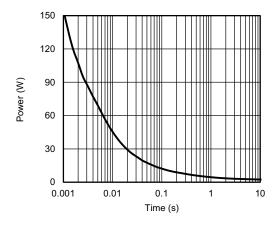
Source-Drain Diode Forward Voltage



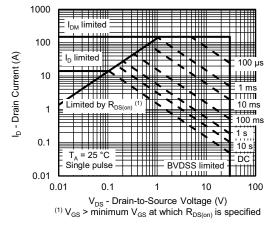
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

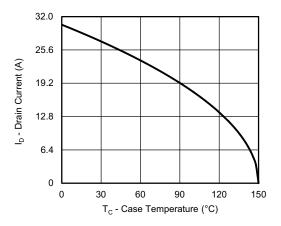


Single Pulse Power, Junction-to-Ambient

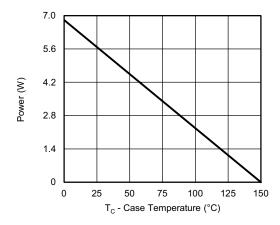


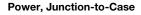
Safe Operating Area, Junction-to-Ambient

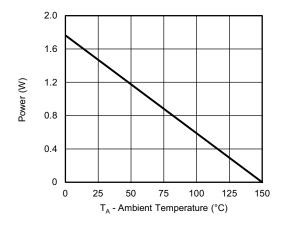




Current Derating a





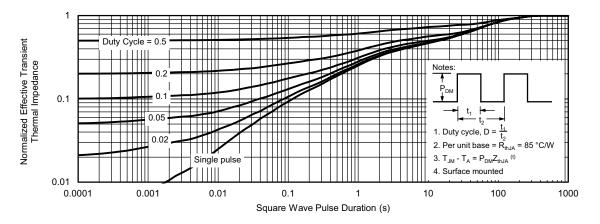


Power, Junction-to-Ambient

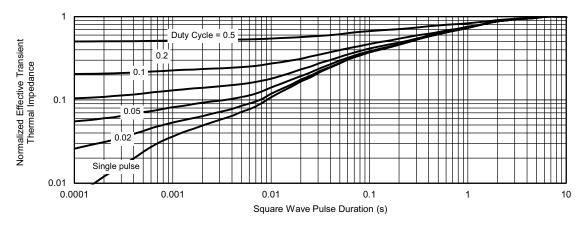
Note

a. The power dissipation P_D is based on T_U max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





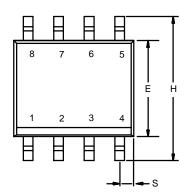
Normalized Thermal Transient Impedance, Junction-to-Ambient

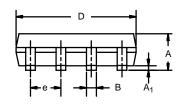


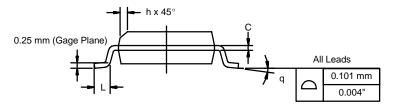
Normalized Thermal Transient Impedance, Junction-to-Case



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012





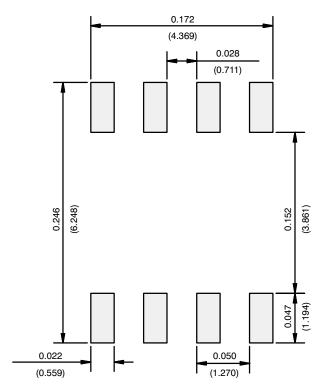


	MILLIN	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27	BSC	0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
TCN: C 06527 Day 1 44 Can 06					

ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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